

# **Notice of References Cited**

Application/Control No.  
10/023,147

Applicant(s)/Patent Under  
Reexamination  
TAKANO ET AL.

Examiner  
EDWYN LABAZE

Art Unit  
2876

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M	US-			

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N					
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## **NON-PATENT DOCUMENTS**

Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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